# EH4945TS-35.328M



EH49 45

Series -RoHS Compliant (Pb-free) 1.8V 4 Pad 2.5mm x 3.2mm Ceramic SMD LVCMOS Oscillator

Frequency Tolerance/Stability + ±50ppm Maximum

#### TS -35.328M Nominal Frequency

Pin 1 Connection

35.328MHz

Tri-State (High Impedance)

Operating Temperature Range -0°C to +70°C

Duty Cycle 50 ±10(%)

ELECTRICAL SPECIFICA	TIONS
Nominal Frequency	35.328MHz
Frequency Tolerance/Stability	±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°, 260°C Reflow, Shock, and Vibration)
Aging at 25°C	±5ppm/Year Maximum
Operating Temperature Range	0°C to +70°C
Supply Voltage	1.8Vdc ±5%
Input Current	4mA Maximum (No Load)
Output Voltage Logic High (Voh)	90% of Vdd Minimum (IOH = -8mA)
Output Voltage Logic Low (Vol)	10% of Vdd Maximum (IOL = +8mA)
Rise/Fall Time	6nSec Maximum (Measured at 20% to 80% of waveform)
Duty Cycle	$50 \pm 10(\%)$ (Measured at 50% of waveform)
Load Drive Capability	15pF Maximum
Output Logic Type	CMOS
Pin 1 Connection	Tri-State (High Impedance)
Tri-State Input Voltage (Vih and Vil)	90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)
Standby Current	10μA Maximum (Pin 1 = Ground)
Absolute Clock Jitter	±125pSec Maximum
Start Up Time	10mSec Maximum
Storage Temperature Range	-55°C to +125°C

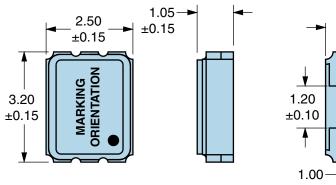
### ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

ESD Susceptibility	MIL-STD-883, Method 3015, Class 1, HBM: 1500Vdc
Fine Leak Test	MIL-STD-883, Method 1014, Condition A
Flammability	UL94-V0
Gross Leak Test	MIL-STD-883, Method 1014, Condition C
Mechanical Shock	MIL-STD-883, Method 2002, Condition B
Moisture Resistance	MIL-STD-883, Method 1004
Moisture Sensitivity	J-STD-020, MSL 1
Resistance to Soldering Heat	MIL-STD-202, Method 210, Condition K
Resistance to Solvents	MIL-STD-202, Method 215
Solderability	MIL-STD-883, Method 2003
Temperature Cycling	MIL-STD-883, Method 1010, Condition B
Vibration	MIL-STD-883, Method 2007, Condition A

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### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**

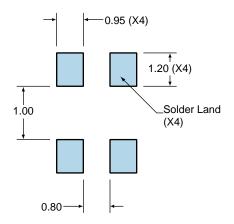


->	-	— 0.75 ±	0.10 (X4)	
<b>_</b>	   2	3		
1.20 ±0.10			1.00 ±0.10	
<b>↑</b>		4		
1.00		-	Ť	
±0.10				

PIN	CONNECTION
1	Tri-State
2	Case Ground
3	Output
4	Supply Voltage
-	
LINE	MARKING
LINE 1	MARKING EPO

### Suggested Solder Pad Layout

All Dimensions in Millimeters

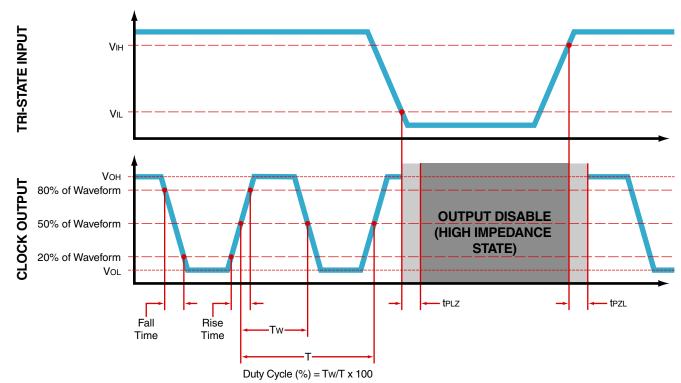


All Tolerances are ±0.1

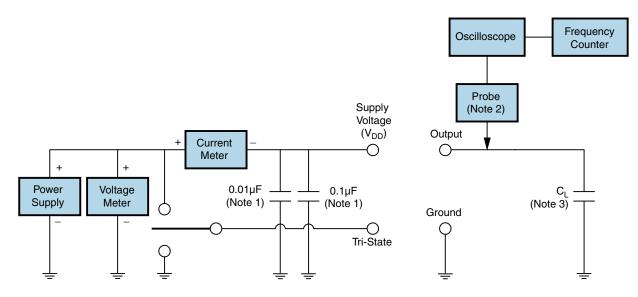
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**OUTPUT WAVEFORM & TIMING DIAGRAM** 



**Test Circuit for CMOS Output** 

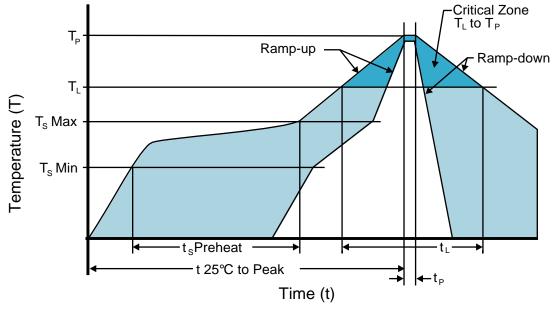


- Note 1: An external 0.01µF ceramic bypass capacitor in parallel with a 0.1µF high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $\mathrm{C}_{\mathrm{L}}$  includes sum of all probe and fixture capacitance.

## **ECLIPTEK** CORPORATION

## **Recommended Solder Reflow Methods**



### **High Temperature Infrared/Convection**

EH4945TS-35.328M

T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)	3°C/second Maximum
Preheat	
- Temperature Minimum (T <sub>s</sub> MIN)	150°C
<ul> <li>Temperature Typical (T<sub>s</sub> TYP)</li> </ul>	175°C
<ul> <li>Temperature Maximum (T<sub>s</sub> MAX)</li> </ul>	200°C
- Time (t <sub>s</sub> MIN)	60 - 180 Seconds
Ramp-up Rate (T⊾ to T <sub>P</sub> )	3°C/second Maximum
Time Maintained Above:	
- Temperature (T∟)	217°C
- Time (t∟)	60 - 150 Seconds
Peak Temperature (T <sub>P</sub> )	260°C Maximum for 10 Seconds Maximum
Target Peak Temperature (T <sub>P</sub> Target)	250°C +0/-5°C
Time within 5°C of actual peak (t <sub>p</sub> )	20 - 40 seconds
Ramp-down Rate	6°C/second Maximum
Time 25°C to Peak Temperature (t)	8 minutes Maximum
Moisture Sensitivity Level	Level 1

## **ECLIPTEK** CORPORATION

## **Recommended Solder Reflow Methods**

EH4945TS-35.328M



### Low Temperature Infrared/Convection 240°C

T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)	5°C/second Maximum
Preheat	
- Temperature Minimum (Ts MIN)	N/A
- Temperature Typical (T <sub>s</sub> TYP)	150°C
- Temperature Maximum (T <sub>s</sub> MAX)	N/A
- Time (t <sub>s</sub> MIN)	60 - 120 Seconds
Ramp-up Rate (T <sub>L</sub> to T <sub>P</sub> )	5°C/second Maximum
Time Maintained Above:	
- Temperature (T <sub>L</sub> )	150°C
- Time (t∟)	200 Seconds Maximum
Peak Temperature (T <sub>P</sub> )	240°C Maximum
Target Peak Temperature (T <sub>P</sub> Target)	240°C Maximum 1 Time / 230°C Maximum 2 Times
Time within 5°C of actual peak (t <sub>p</sub> )	10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time
Ramp-down Rate	5°C/second Maximum
Time 25°C to Peak Temperature (t)	N/A
Moisture Sensitivity Level	Level 1

#### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

#### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum.